LECTURE NOTES ON

## VLSI AND EMBEDDED SYSTEM

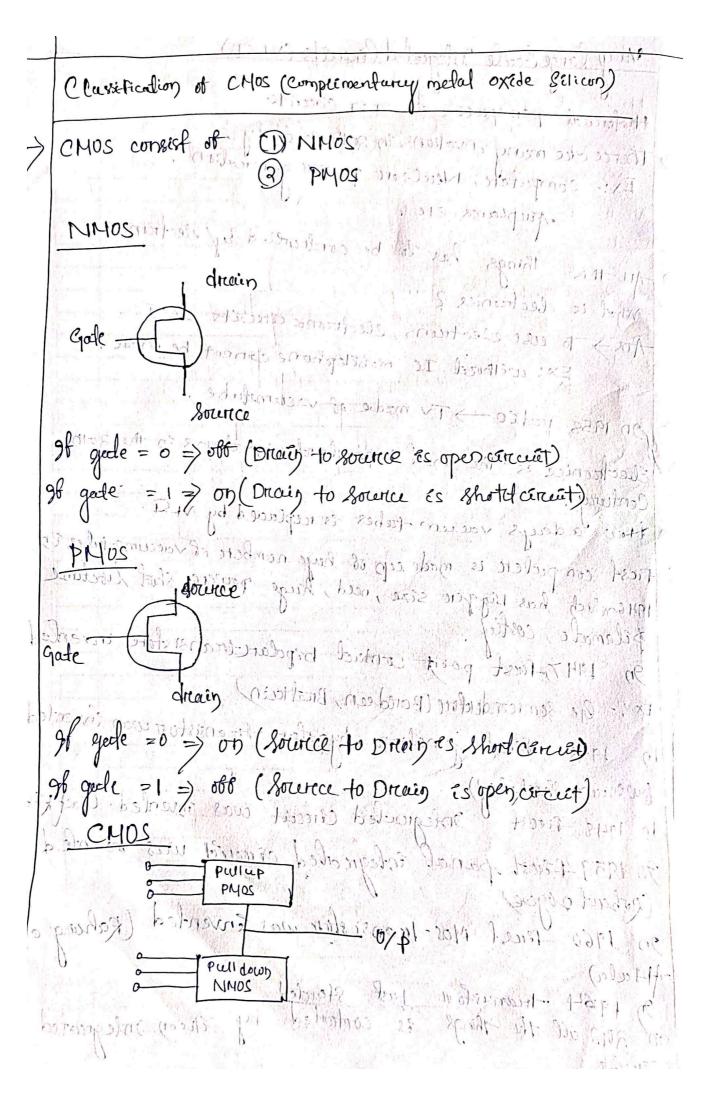
## 5<sup>th</sup> SEMESTER ETC

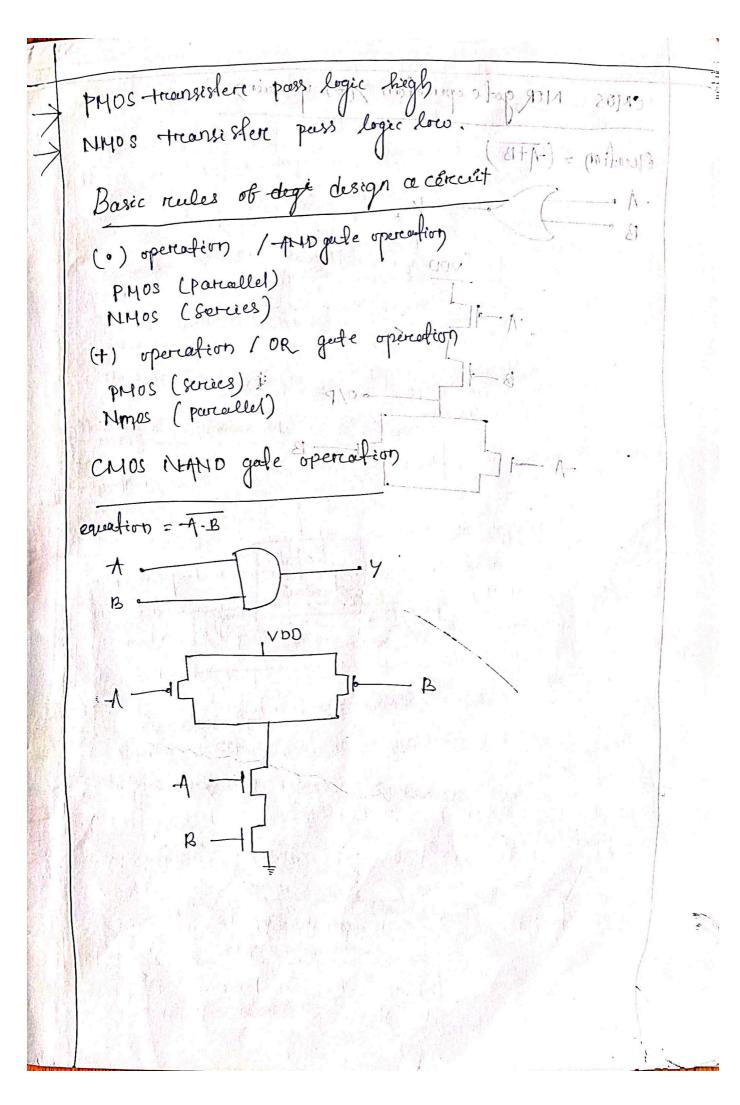


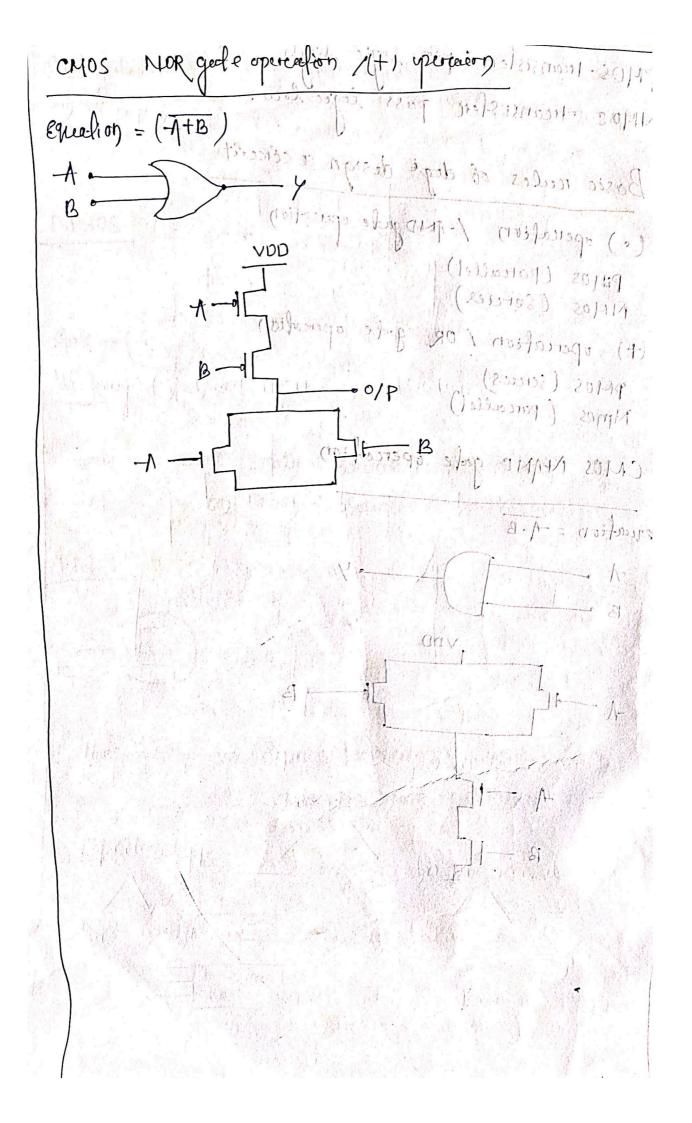
Prepared by: Anchal Sundar Ray

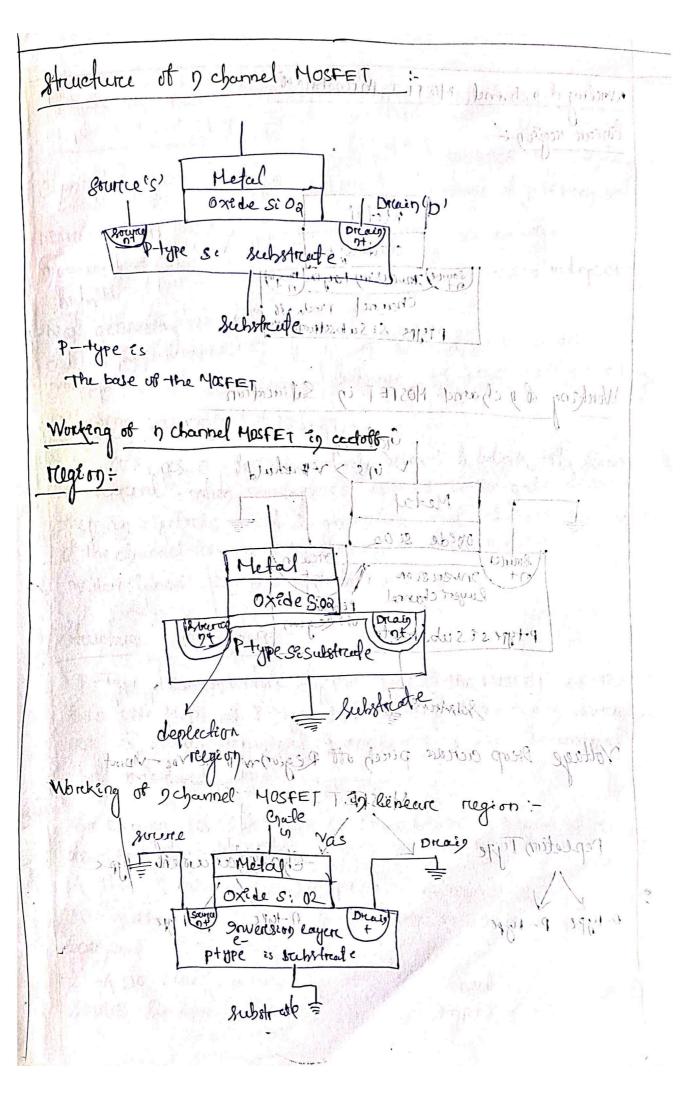
GOVERNMENT POLYTECHNIC, DHENKANAL

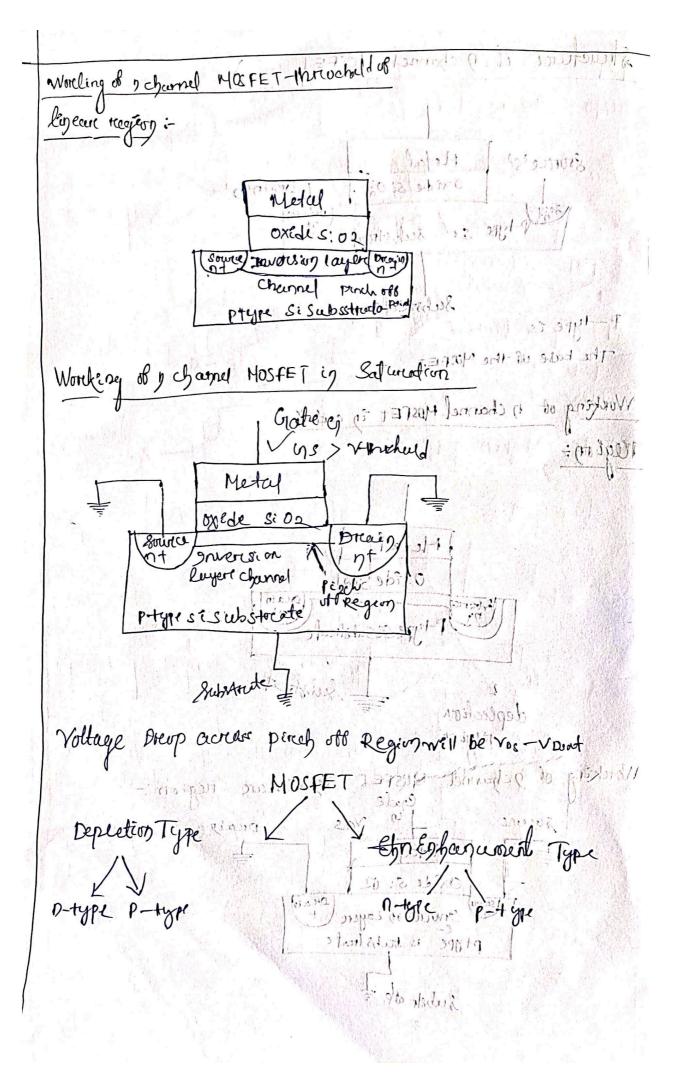
Very large Scale Integrated (Excusts (VLSI) housist objection of CHOS (Comprenenting of the Oxide Dillion Historical perespective of VLSI Circuit: > There are many Envalions in 2014 Gentrery , to fish 20145 Ex:- computet, Neclear power generadion -) All this things has to be contralled by electronics in What is electronics? Ans > to use electrions, electronic cercuits ou Ic. Ex: wethout Ic mobilephone can not be made ?! 90 1958 readio - To made of vacumetube > Electronice is the most importantissinjuations in the 20th Century to sounce is shorted con minimal (mo I How a days vacuer takes is replaced by NIST. > first computer is made exp of huge number of vaccume-fules is 1946 which has bigger size, need, huge powere; short libetime pElamorte, costly 90 1947, First point consect bepolar treansistore invented. Ex: - Ge semiconductore (Boredsen, Breattain) (1500) 19 1948 - Firest jeunchion bypoleure transistor was invended. In 1948 Firest Integreeted Cercuit was invented. Gack tilby In 1959 first panal integraled corcult was inverted. (Robert soyce) In 1960 fined Mos-transistor was tenvended (Rahung and (Haler) Steveled 2014 In 1964 transistor just on all all the things is controlled by silicon integrated









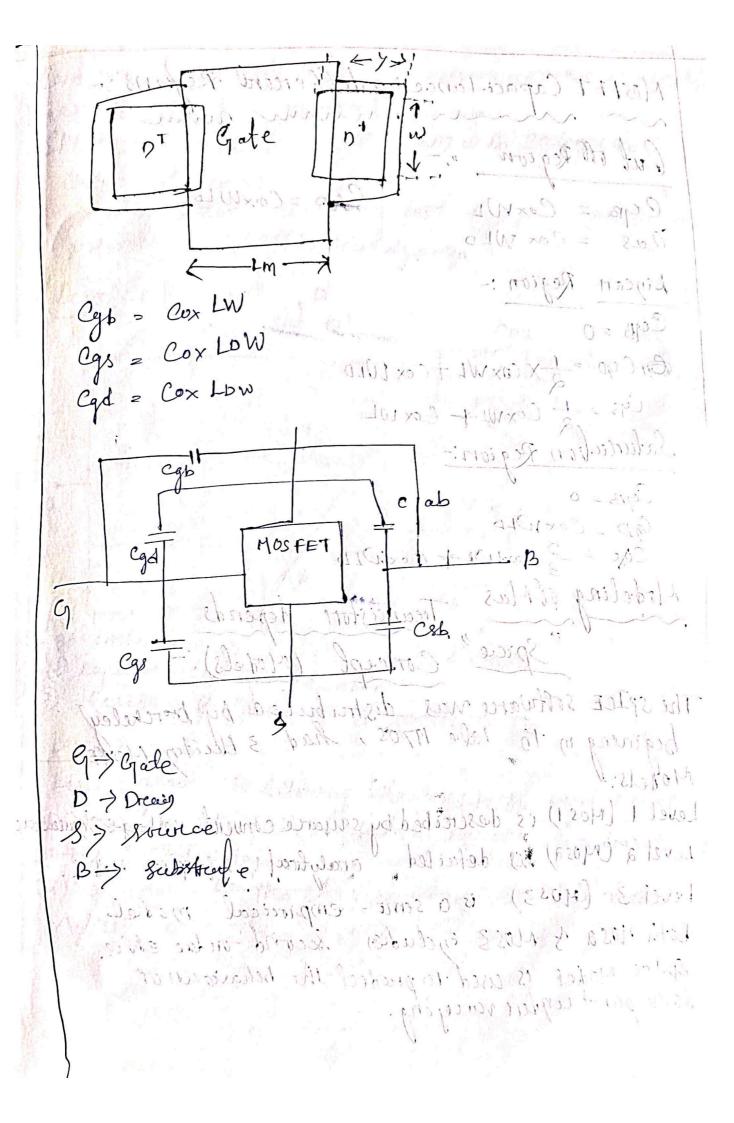


TIME I Enhancement type day Deplection Type 1 channel is cohance by appeared channel is present by applying vortage al gateternizal. 2. Normally ON odvice d. Horoncelly off device 3. mobelify of Canciers is 3. Less in competer story to deposition high! 4. Not generally used assivited Lype due to high Vithoroshers H. It is used as a switch, because of low terinigal nottage. Working principle of Mastelli It act as a swetch which allows & bedock the stown of cercrent. when voltage is applied to the gate termingal, then an electric bield is genraled that changes the, width of the channel region & tends to flow the electron's. Weder channel - betfer conductivity Enhancement. Region Shuckure of MosfEtilos 9.505115 P-Type semiconductore is the base of the MasfEt of the 200 side (top). of P-type two heavily doped region borom. (both are doped with p-type computity) The layer of substrale is coaled with a layer of selicon doxede bottomscillation: A they ensulated metalic place is kept on the top pt-the Ellicon déoxede 4 21 oct às a Capacitor trom which gette bernningal is creveje, aled. -> -A DC cereal is then boround by connecting a vortage Southe buchusen there two n-type regions

Symbol of N-Channel MostEt Enhancement ... P-Channel (MOSFET) postale so to more deples of the property Then an electrice sied at miceled that is no man of the especial regists of the office of the steder charact - Spottle conductive is Enhancement mode Openating) Regions 10th HOSFET 131- 2: 270/206/102/1021 39/07-9 Region 1 mond out sept 1 1 - (got) 3652 5013 In this Region there will be no Conduction, Mosfet was OFF. In This Pegin Mosfett behaves dike an open swood D'ohimic Region / Active Region / Active Region / ctive Region (lineaux Regions: 1 363xor Here, they current Ips excreases with specease In the value not vos 39 thes region, they are is most -A De circuit is they borond by common a i contra Surfile Buckeyers That

3 suturestion Region In This region, MosfET have their IDS querent in spaye of an increeix in vos and occurs once vos exceeds the value of pigch-off voltage vp. 29 this Region. Most et ad like a closed switch through which a solvented value of IDS Slows. Swetching Characteristics Top linear Vous LODON Vas = 0 N-Channel. OFF ON Enherement OFF UN ON N-channel Deplection pr-channel, ON OFF Enhucement P-Channel Viss svas- Tro Deplection > 1 ON Application of Moster :- - Taron to pastin Radio frequency application. 21 tours belonget to beight MOSFET behaves as a passive cincult Element used to rugulate De gotore in almost and mes and The degy of the chopper circuit. Advantage of Moster : has been pleased on operate at greater efficiency of lowere voltages Asence of gate convert regults in high Input Impedence preducing high switching (35) NOHERINE 181-

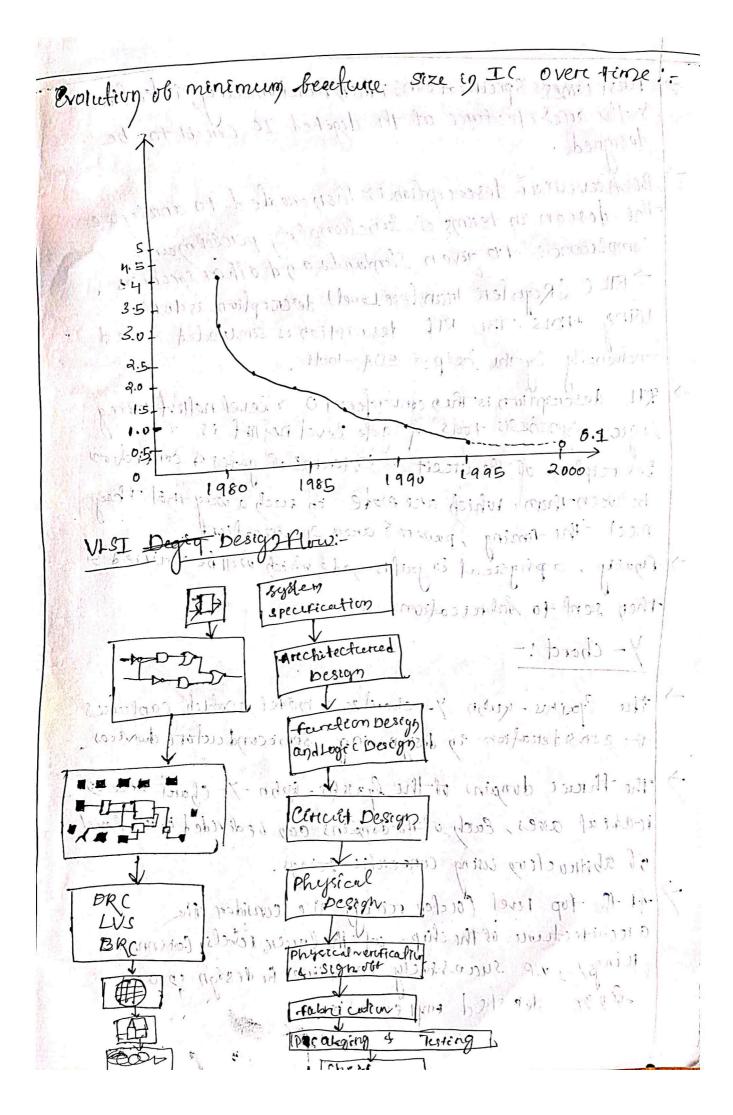
Disadvanlag of MOSFET in certain Mochet Four Assum Dange by Electronic changes due to the A oxide layer. overllaad voltages make Mostlet unslable! MOSFET V-I characteristics: Suzztahing Charicelerifics Top Lineare Saturation \_\_\_\_\_ VDS = VYS- PT Wi ID & VOS 100199 Working of Mosfet Capacotances 131011 to 10120011111 speed of integrated central is lemuned by capacitaines. Thise Capacitancies s'arce not leemped mul distributed. 9t1 8 values ceep be calculated by three mensional arranged The death of the chapper societ of Mosfet. Here, we have already studied cox which is gate capacitance, l' «+13 unit is PF/cm² Crale Cox = Eon les said Joseph of P-Type substrude (Si)



MOSFET Capaci-tence in different Regions: Out of Region COND = COXWLD CGB = COXWL Cas = Cox WLD Linean Region:-CyB = 0 61 CGD = X COXWL + COX WLD CGS 2 1 COXWL+ COXWL Saturation Region: Ceps 20 GD = COXWLD Cys = 3 CONNL+ COXWLD Modeling of Mus Spice "Concept (Models) The SPICE software was distributed by brencheley beginning in the late 1970s, had 3 bluden Most Models: Level 1 (Mos 1) is described by square convert voltage Characteristics Level a (Mosa) is defueled analytical plosing st Model. Level 3 (MUSZ) is a semi-empiraceal model Both MOS & 4 MOS & Encludes Second - onder effer. SpITE Model is used to predict the behaviour or some part under varying.

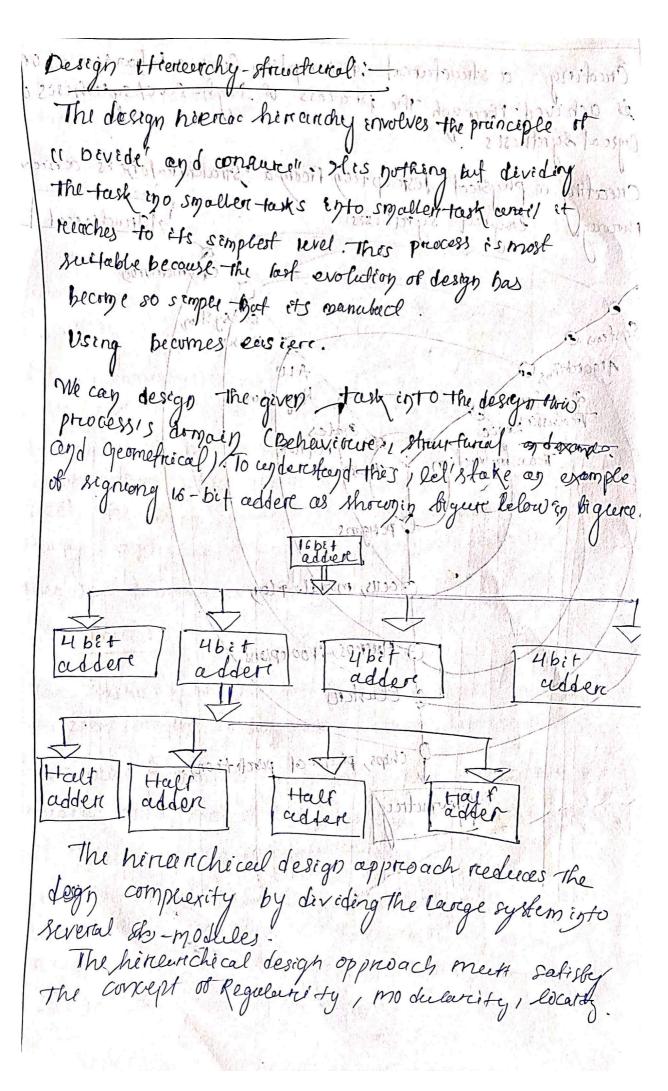
Canditions by The help of SPICE semulators, where we use ex Lescription of a concernent tomponent to SPICE > Simulation Program with Integrated Concilt Emphases If is a look used to test designs potentially costly protetyping Francos of Conspination Level-1 CGD VDB TD VOS Device + VCB- 11/k: )((100) 2012 1999 91 includes (1) resistance of source 4 preseg @ ceyzercitance (boas dependent/1010) 3) Revese - Bias behaviore of Junction Divde Level-a .-Level & ced's The bollowing behaviours to the Level 1 model (1/ Varieties of the bulk deplection Charges depelance (9) Varieation In the channel voltage of Electrons mobility with the applied E-boels

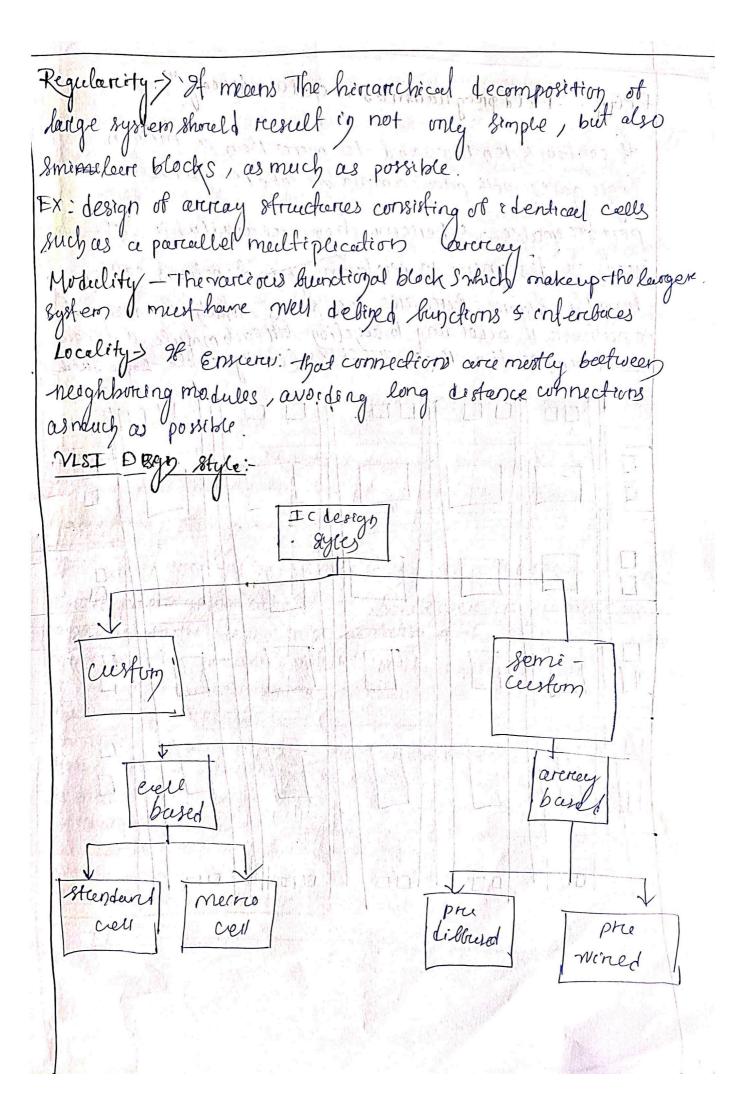
Vareiation of corrective channel length is saturation mode Carried Velocity Satisfaction Sub threshold Conduction Level 3: Hevel 3 was descriped to specifically address geometry effects. Bitting paremeters are wed grerceesing Device Physics Device Electronics Two-Treansistere Concert (Envereleus) combigational & secrential Logic cincuit Adders, rultipliers ROMS/RAMS, PLAC Rystem-Related Issues, Reliability. creadth of Topics



> firest comes specifical ions, Then functionality, interchace I the architecture at the degited IC cencil to be designed Be heriorcal description is then created to analyze The design in teams of bunctionality personnance, Completence -10 given Hordands and other specificas > RTLC (Registere transfer Level) descraption is dome Whey HDLS. This RTL description is simulated total henchionally legate help of EDA tools RTI description is the convergent a level notist using logic synthesis tools. A gole Revel nethist is a -. description of the creek: (1) terms of gates 4 connections between them, which are made to such a way that they meet the fining, powers area specification ) Finally, a physical lagoritis made which will be verified & then sent to babracation. y-chard: the Gashu-kubn y-chartes a model, which captures the consideration en design-ing semiconductors dienèces The three domains of the Gassier-fuhn-7-charit arce of toads at ones, Each of the domains can be divided into level. of abstruction using concentrations. 7/1/1 the top level Confer ring; We consider the archotecture of the chip, at the lower revels beginners rlings/, we successively reductive he desogn 1910 Sign detailed emplemention !!

a structureal description brom a behaviore at one is achieved through the process of high-level syntheses orc Creating lycal synthesis Creceting a physical description-ficon a structuratorse is achieved layout synthesis thowage Cpy memoring as of descen bas its wandlock scelsystem, Systems & 2. Bases out the sal Algorithm Regulatorill applies (10) 110 Registere Treenster Logic dinja Treamsforchunching They store files of the bett ordife POHgons Jaus, module plays Hockos, Froomplans Elester Chips, physical partitions. Germetry . Her Micros hesign appearance reduces the of the eding the large in seeing into

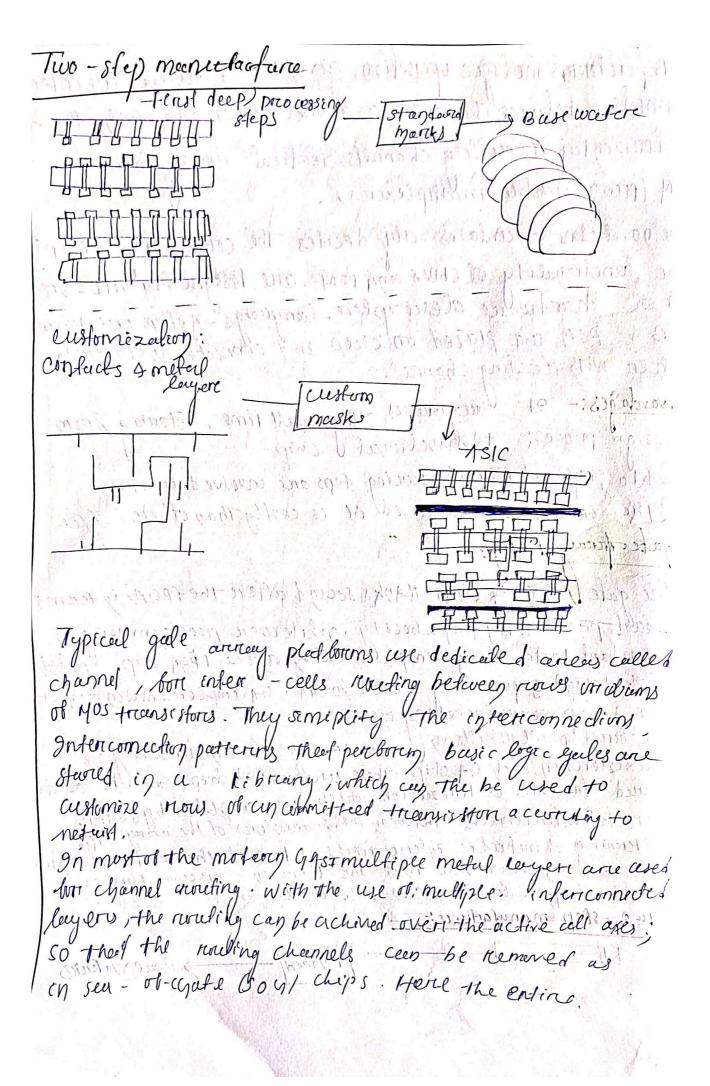




FPGA: "Field programmable cectu Armay": 11111 It contains len-thousand to metathern a mellion logic gates with programmable interl-connection programable. Enterconnection are available bore Mseus on designers to personing given benchions easily.

Inom the Biguero, There are I/O blocks, which are designed to numbered according to benchion bott Each module of dogs level composation, There are cers (consignable Logic due

CLB perchonens the logic operation given to the modele. The intere connection between CLB and I/O blocks are made with the help of horizontal reacting channels, verifical routing channels of PSM (priogramable malliplexers). The 90. of clas it confains only decides the complexity of fp91. The functionality of CHO'S and PSM are designed by VHD Love any others heard warre ales craptire-language - 1 ster programming CLB & PSM and placed on chiep and connected with each other with tracting channel. Advantages: - 91 requarites very small time; starting strom design processos to bugchiogal of chip. DNo physical manufacturing steps one involved in it 2) The only disabboartage is it is costly than other style. Gate frency Design: The gate / Arrany (GA) Kanks second after the fran in terems of fast prototyphy capabicity, while were progressming is important to the lesign implementation of the FPGA chop metal mosk design & processing is used to 44. an implementation requires a two steps meencerfactuating process. The birest pheel telrelts in () an arrowy of ancommenty thansistoris in Each GA chip . These withmetted chops can the studied Stored for later customizeet con, which is completed by delining the metal intericonnects between the mansistons of the array patterning of metalic infericonnects is done at the end of the cry fabrice the process, so that the the suren -Still be short, a been deays to a been weeks. Two step manufactions Two step manufactures begins the merily our reactioned an Hours The Extines



chip surface is covered with committed nyos PMOS treensitors The neighbouring treansidors can be certonized using a metal musk to boring basic legic gales. - For in test cell to routing, some of the uncommitted meinsistons must be sacrified. This design style results in mone blexibility been intericonnictions and usually of a highen density of chip utilization-kector is measured by the ared Chip area divided by The total Chip area, It is hegere Though I hat of the FPGA 450 is The chip speed Standard cell Based Design: A steendeerd cell based design requeres development of a bull custom mark set . The staggered cell is also knowing the poly(ell. 9 h. This oppreach, all of the commonly wied logic cells are developed, characterized & stoned in a Standard cell library. A librarry may contain a bew headred cell sing clubing enterfeurs, NAND gabe, Xlor gabe, complex, ACF, OAF
gabes, D-ale detches & slip-slops beech give type ceiphe emplemented in several versions to prieve de adequele drieving Capability: Son dibberent sten-outs The inventen gate con have standard size, double size, and areadrepse size sothat the chip designer can seed the proper size to obtain high cercuit speed & layout density Chenacterization certogories. Such as to servert diff. -) Delay time versus load cerp acitance - Cincit simulation model.

Timing 11 - Timeny aell duta - son place and route. I mark duta.

	The second secon
	- Por automated pleicement of the alls 4 nouting, seed all
	launced is designed with a fixed height, so that a now
	cell can be bounded side by side to born rous The porter
	agrirand rails run parallel to the upper 4 lowers
	buindries of the cell. So That, meighboring cell sheer
	a commen oraced hus
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	Standard - Cell Row J
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	full current Design : of respective tions is both more than
	full custom Design -
	In a bull-custom design, the entire must design is
- 15	Though the solution of the sol
	dievelopment cost of this design sty Cie is relowing Thus
	the concept of design trevese a becoming burnous do
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	The hardnest bell crestom design can be the
	The hardnest bell coston designate be the lesign of memory cell, he El state on
	A My Wight Chip ( estily) / Ce job is region
	he objectives of a compensation.
	can in

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110/11/

of di-French diosign styles contine same chip is e standard early doto path cells, & programble ergic coveries (PL+3).

producelly the designer does the full custom layout in the geometry, origation as a placement of every transistors. The design producement, is welly very low; typically a few tens of transistoris per by, per designer. In lightly come for the logh labor cust there design types include the fest on of high volume products such as merrory chips hegy performance microprovissors & tops of the sign performance.

Simplified process seasonice:

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I on implantation who process of adding impunctions to

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These steps and somewed by the committee of graph s

of such exempt welation along is dent incomes according to tool to too consume to

50 11	(HAPTER-2
	F-ABRICATION OF MOSFET
	Simplificed process sequence fort-fabracoulton:
7	CMOS-fabraicection rechnology requires both Timos and prous transistore to built on the same chip substructe.
$\rightarrow$	To me and the first stress of proceedings on must
	To accompante both Hmos & pmos devices special regions must be corrected in which the semiconductor type is opposite to the substrates—type, These special regions are called wells on takes so, a new is burned in a psubstrate & a simplified
	puell es boundaig et substade.
	Simplified process sequence:
$\rightarrow$	The process starts with the creeklon of the nwill regions
	for pmos ond pwell regions for Hmos by ion implemedion into
1	the substocales.
-)	I on implantation is the preciess of adding impunishes to a
1. P	Siliun water.
7	Then athick oxide is grown on the regions surmounting the NINIOS & PMBS active regions, that then gothe oxide is subsequently grown on the surface through thermal exclusion.  Again a physilican layer is desposable.
	Subsequency group of the surface through thermal exchafica
-)	-Aguin a physillium layer is deposited on the
1	Aguin a physillium layer is deposed on the sareface of the oxede layer 15th & selectivity removed to form the gats.
7	These shaps we some wear by the correction of 51 and 67
-)	At last ment oretalization is done main oceating of
	metal coterconnects.

metalization is the process by which the components of Fors gette enter connected by alienenium andictores to hasing 10 2; channel stop, implant is wild to prevent the force action of any unwayted channels felween two neighboring regions, Hence Channel stup implants act to electrically is duffe neighboring devectes built on the same, substance Create n-well regions 4 channel-stop regions Grow field oxide and gale oxide (thin oxide) coling Elostet attracci Deposit & pattern Polysilian amplant source & drewn regions Substrate untacts a pattern metal layer of ballo 25 (1) Basic steps of fabrication 7 The fabrication cycle for 15 in chip's consests of a sequential set of sexcential set of basic steps which are water preparation, exedution, eitherrouphy setching. During babreiculium process, the devices are created on the chip 30 It may be viewed the thip, so, Ic may be viewed.

$oldsymbol{\lambda}$
as a set of patterned lougens.
- A layer must be partieraled before the next layer of modercial
S.C. On in D.C. O. A. Arthornia D. C. D. C. C. State Company and C.
> peet-terring uses, the process of tog lethography The process used to truensper a partiern to a layer on the clip's called lithography.
celled icthography. Januaris of Asis Insigen quis larroads
- The 10thogrouphy sequence must be repeated for externed
5. Fabricedion OF Mosfet Date: 7: 08: 2012
-feebrecedton process:
Februication process:  Sold has a horizon blood on the state of the st
for Fabricating MosfET different process are used.
Setep-1
and the heterolo wester chip is taken . The larger
must be patterned before the next layer of material
es applied on the chip
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Salstrate properties
p-type de
The process use to treensfer a postery to a layer on the chip is called lithography. Into a layer on the
chip is an
Step-2 (131/2015/da) 1 15 292/12/2018
I The silicon surface is oxedie by using oxidation process to
The silicon surface is oxedie by using oxidation process to form an oxide layer on this street, santice.
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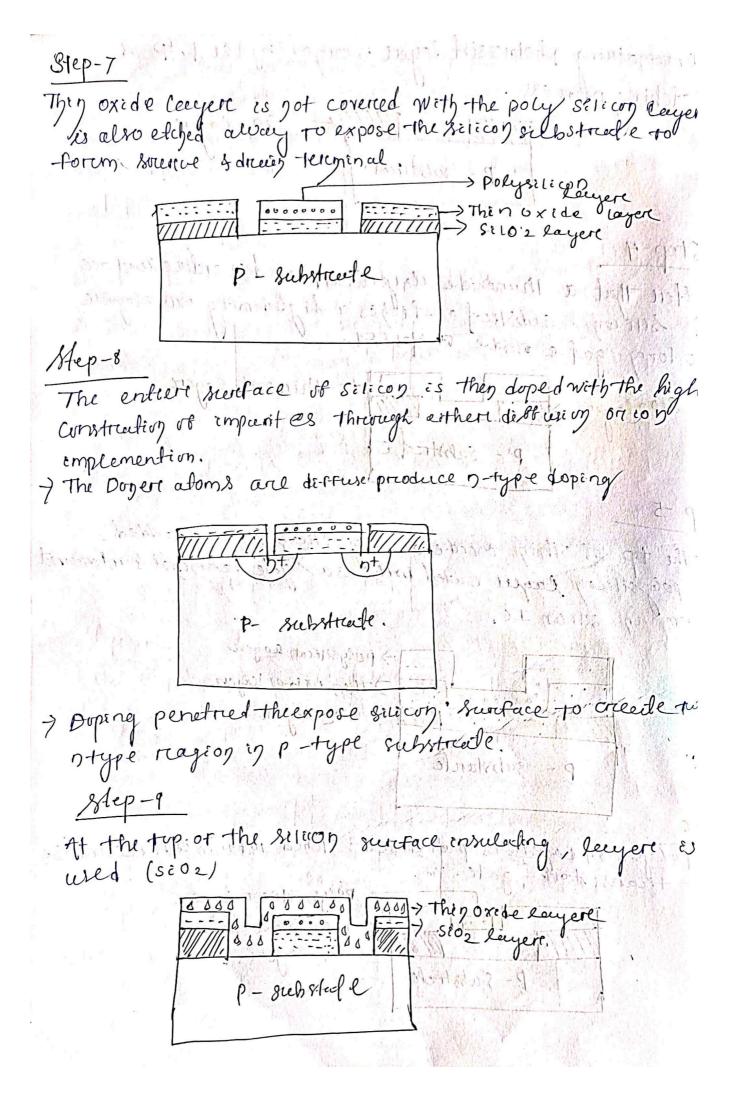
on the sureface sion photoresist layer is added which is semetive to The light. Si-substall > The photones ist layere are of a largeres (1) positive photograsist lageoc (2/ Negative photorcerist Layer -> when photoresist coupers come in construct with light & it is soluble, then it is called as positive photoriese of leaget. ) when photoriesist layer come is contact with ultreavolite light it is insoluble they it is called as negative photorexist layere. 12 115 3 Dent & 16 - 6 Vsuelly positive photonesist layer is used -) to temore the photonesist luyer & silicon dioxide layer pass through a traspurent (Si Oa) the cultranolite light mask in which both the sides one gon treensparent.

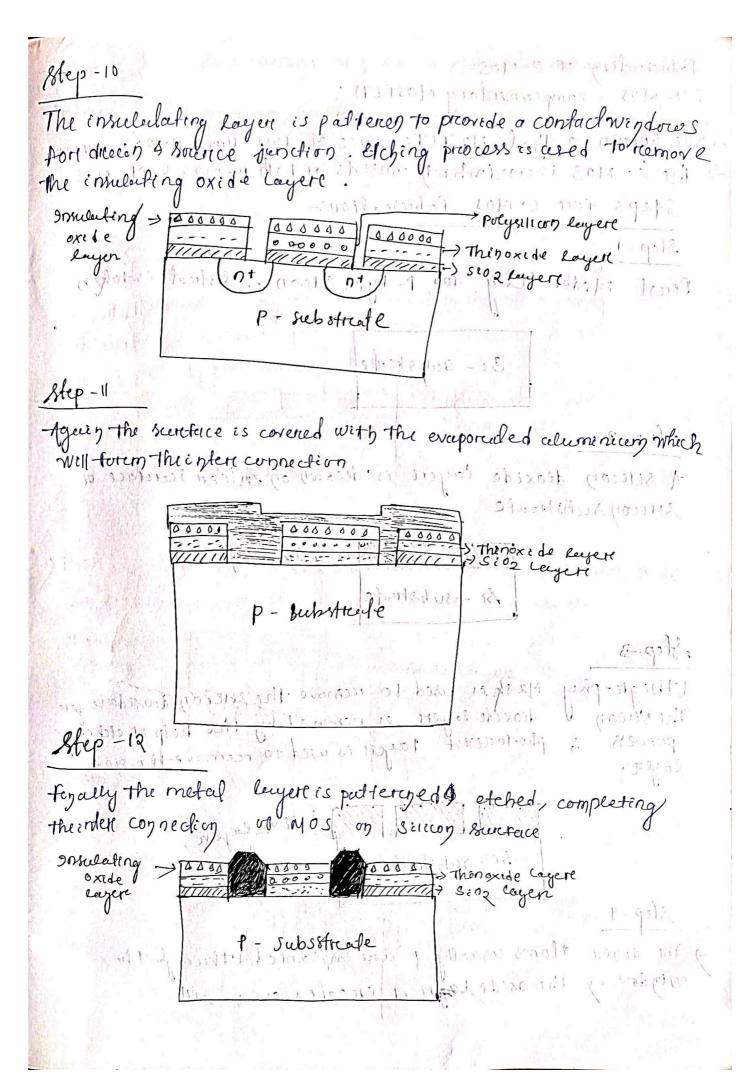
Photogenist cargon

Leyen Sioz layere P-substrate Stap-41 And smotorial out to glod intige good A sten the step no. 3 photorcesist layer is prevent on both the side. The photoresist slayer can be be remove by a Salvent (Hydroflunk Acid) on plasma etch P - Substreal

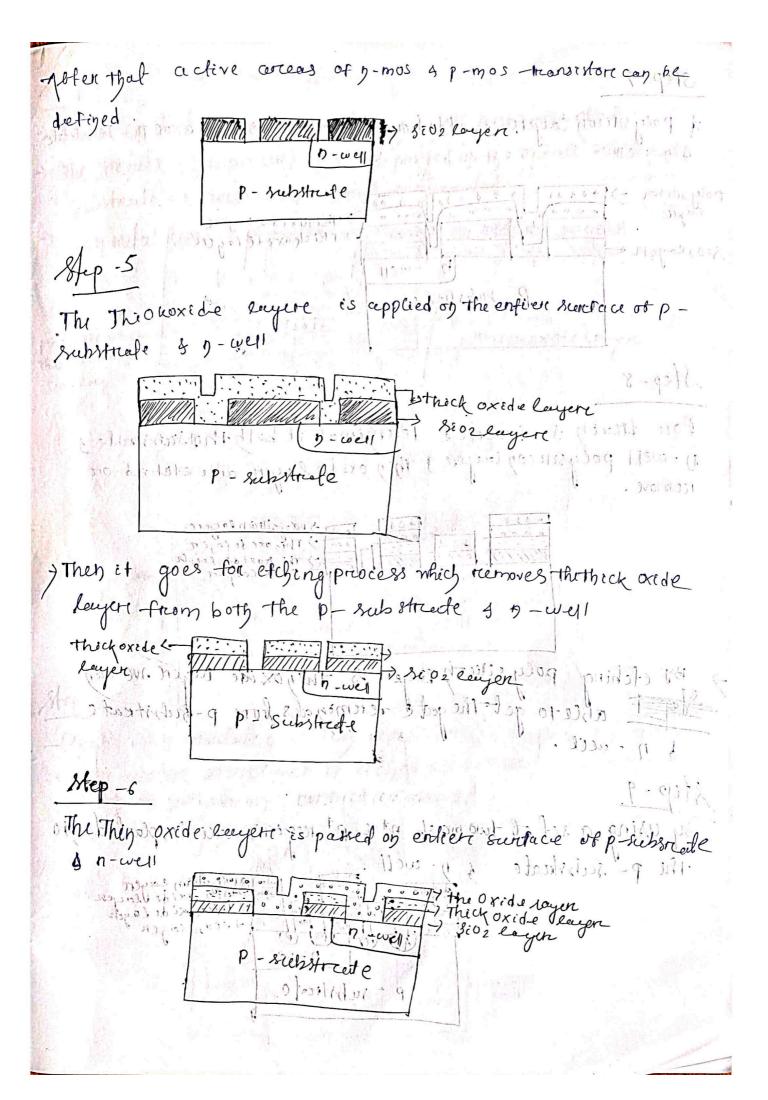
tremoving the remaining photonested thom sion
The process of tremoving the reenaining photonested from sions sureface using solvent () & leving the pattern on the sion
2 a ll 000 las atché and re-section
>- For accural generalion of high density.
Fabrication of 1-MOS: - 37-120 1-120
Step -1 sayou Hissori Hissori (1)
A Thick silicon waser substrute is taken which is p-type
and the scenarage of serion is patterness transford and
P - Substrude (Silicing)
Alendary Marian and Compared to the second s
esteption of a substreet e on silicon -
Add sing of the surface of p-substruct e on silicon-
Subristrute by the help ob Onidrum priocess. The scentace
not siognisis parterened in majoris stational solutions and the constitution of solutions and the constitutions are the constitution
Sioz Cayer
Pi-Substreate 1
Step-3
Remove the 500 by the help of the photorestist layer.
then the cultimer volite leght is passed through the help of mask which is non-transported at both the sides
mark which is non-transported at both othe sides
transparent at the middle of
11/1/1/1/1/1/1/1/1/1/1/1/1/1/1/1/1/1/1
P-sustnate Cayen
19 P. L. L. L. L. 11 P. L. 11 P. L. 11 P. L. 12

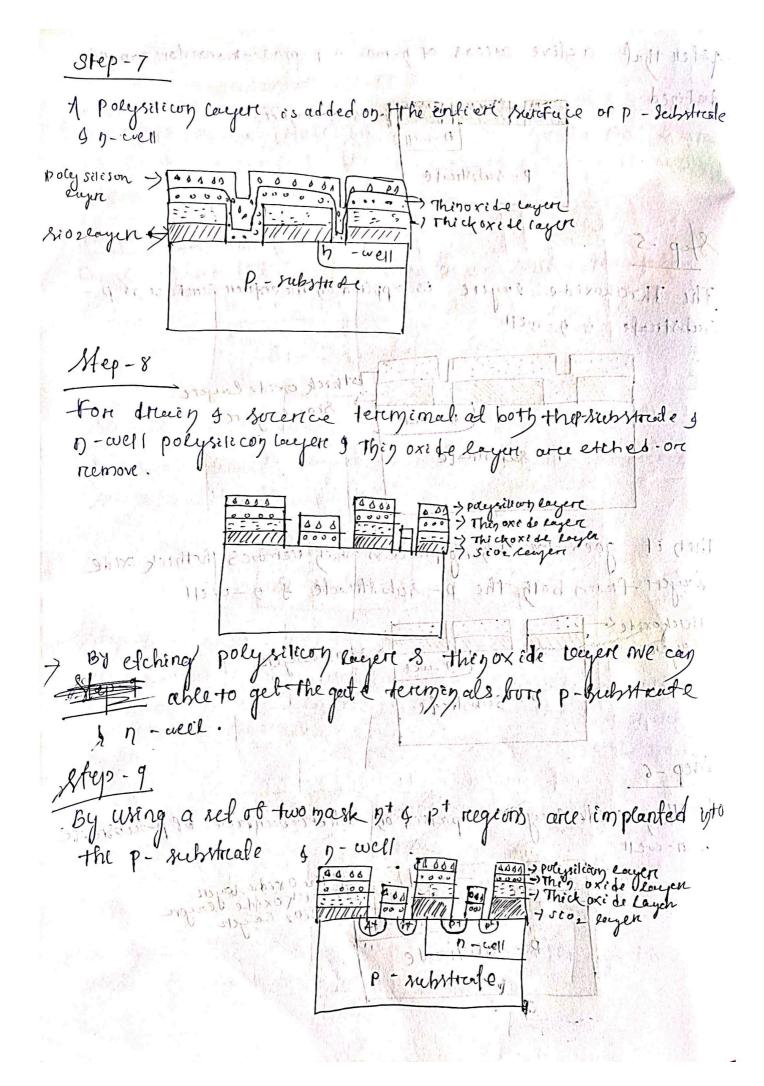
I the remaining photorcesist layer is remove by the half of
eatching phocess.  [7]  Sio2 lager
10 10 13 1 15 10 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1
P, = substruit e
Step-4 the movide clayere is passed on entire severace
Step-4  After that a thunorième clayere is passed on entire sever ace  After that a thunorième clayere is passed on entire sever ace  of solicion - substrail e which is a high density oricle loggere  to-form gaf e orième of MosfE1.  The novoble logere
to-form gaf e nide of MosfE1.
7/////
p - substruct e  Mep -5
South the same of
Step 5
Mep 5  On the typ of thin oxide a poly silicon leger os added.  The polysilicon layer is used both as a gate recognized & interconnect medium in suicun IC.
medium in suican Ic.
polysilicon layer
then write layer
1000 - 100 -
P-substanle
Step-6 The polyphicon coyer is patterned & etched to form intericonnedss
MOS - treansi stort got.
Theo oxide layere
P- Rubstando
1 3 colo 1 la [ C ]

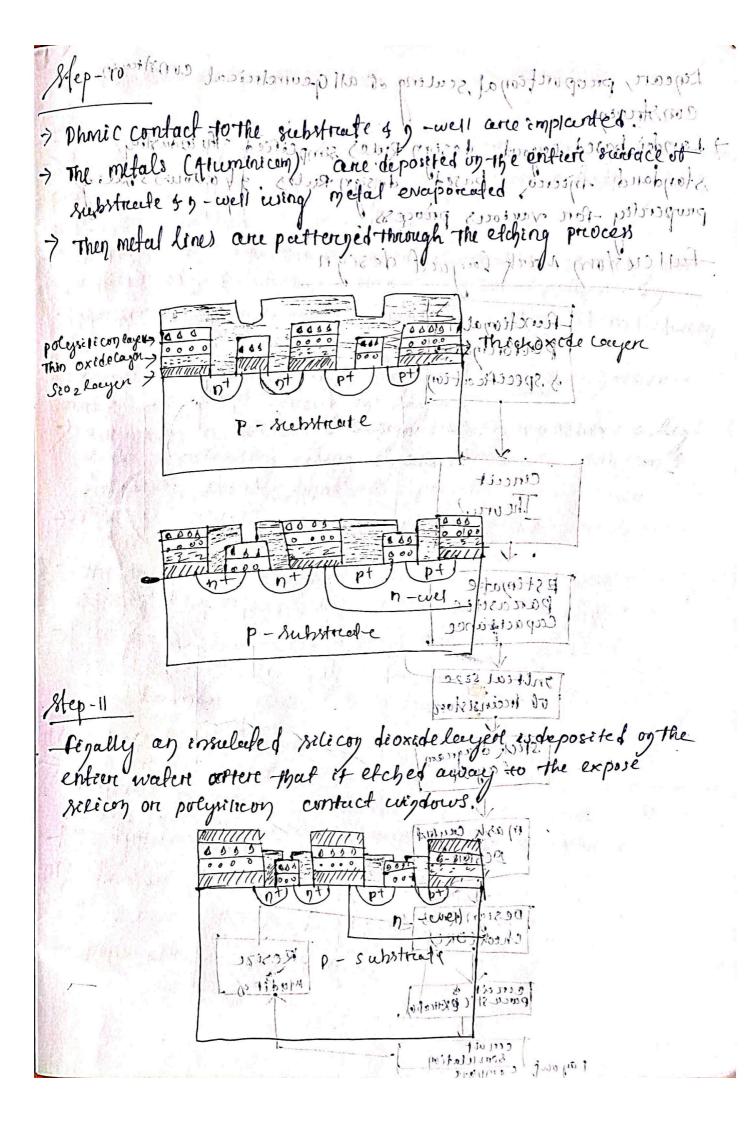




-Fabraication or C-MOS	33:
(U-NOS - comprementary MOSFET):	
> We known o that Mosrets are of two types p-mos 4x	5 .
> The course is the fact and it of both pomos 4 None	1005
> The c-Mos is wed which consists of both p-Mos & N-Mes	ST
34eps for CMOJ - Februation:	re.
Step - 1	Ď.
First Moderately dop P-type selicon substrate is taken	)
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3 Step - 20 10 500 h s honogons later golden honor of bandouse Mary	
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window in the oxide layer it creates a newell	







Lipeare, proportional scaling of all geometrical construin. Construent organismo 1100- ( 1) statition still of 7 Lunder based leyout design Rules simplified Standard micro based design Rules glaubus staling property for various process - this actor was and poetlery of thomash the ething tull custom Mark layout design Functionality Performance & Specification D. Hospiledoskie A ancuit Theory Estimate paraseti c Capacitance 12 - Substroke Inttal size of treensistand sit po batisog stick diagreen ". Uy an insulated Wilicon dioxide receive except or except of etable of appoint in experie ical ou bachistican consuct enidoing! mark cayout Desino. Design Rues Check (DRC) Resize certait & parentis Modific Layout, compere.

Lauvert design Rules Laugout of any cincuit to Maniefactor cusing a particular. process Most conforcem to a set of geneticis construintors rules and Collect as layout design Rules. The Rules specefy the menemen devouable Cape wedth force physical object lonchip such as metal spolysolición interconnection minimum allowable separation between two such beatieres. Example is if two lines are placed closed to each other it make the short circuit in layout I the main, objectives of design rules is to achieve a high ejied & relubility cesing smallest possible sillicon's relability sising smallest possible sellicon area -) There is usually a treede of between higher yield s better area efficiency The layout design rules increases the probability of bubricketing a successful product with high yield. -> Usully design rules are of two types these are (1) Millereo Rules (ue-Rules). [ii] Leemder Rules ( & > Rules). d' Micro Rules (u-Rules): Then Rieles in which the layout constraint such as minimum Then keeles in which The coupour comments of reception are stated in 199 Mecro Rules size is fixed in Micrometer. (1) Landu Rules (Miquey) It specify the layout construent in f paneemetter com der 4 allow

The design of locyout as very eightly eightly line for the percet or companie such as I speed, oncea, is ploud discipation in Physical. Mittercherce dereachty delimines the treens, conduct for once The mask layout design is process which starts from

-frenchionelety, pertformance & specificaction of legic coglete (s) Then it state with cereit topology timece ved diseered logit trenchion. It estimat i matels parasstici capacitanio Then it indi- inticalises the siling of to realized desearced perstormance specification. Then a simple stick di agreem showing the location of continuet TAffere state a topologically, visible layout is found Mesh beyer are drewn, according to the layers -) After follow in of designales it goes bor design Rule checking ignifich the circult extreaction processing is perform on finest layout. Defermine actual transistoresized parasitic capacitance at each anode. Then of goes for concuet somulation by using spick Tedenology determine the performance of condit of there is any field in circuit & paries it i capacestance then it is goes I son Resize & moderication, offen mat We can able to get a complete layout de sign som coup fulter ( xer fectors): Stick dragreom: maker is a single of the respect to the distance ) It is a levejoid of showing locade in of treens tons , 13 local inferconnection between the transistory of Confuct -) 9f is very difficult to find a Minimum area lengert for complex c-mos logic circuit of To avoide the drewback of legout design stick diagram is used

To avoide the drewback of layout design stick diagram yit 2011 nsed -) By the help of stick deagreem we can minimize the so concition complexity can be treduced. 1) - 102 Engrencentent Icho: -) If we can minimize a no. of diffusion areen both for n-mos & pmostransition spanoeting between poly siliter get es can be made smaller which is reduce the overeal horizontal diamentions 1 - Stepstor (ca) Cincuit lengout arren. The standard of any of the modernoon of the form to many and the subject of the angent of the contract condending storned will be formed telineral trenders interest of the correspondence of the property of the districtions of the distriction of the distriction of the distriction of the distriction of intiment diccin is summed in the confier of charmel remark. -) The level erecel assent of Velovace is Chounces width ) of NOS Means store has noc indirections. Champel recoiled tell will gut & bias - so it is called as I so incoment right host si of the conducting themsel exist at zer wyell beaster cally of channel 4105-Ver Herce Definition of the Color (1) Description of the strained 3 7 Socarec 1 creminal 16 - Substante this od is again sound steered anough a police show. A Sunte may Ene 2005 - Price 9 - 1800 1:5 301 tage 1155 -> Substitute - Focusion Vittage